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FORM PTO-1449	SERIAL NO. <del>Not Yet Assigned</del> <b>10577175</b>	CASE NO. <b>1990540</b> (BIF115433/US)
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE Herewith	GROUP ART UNIT <del>Not Yet Assigned</del>
APPLICANTS: NGUYEN et al.		

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
	A1	US 2004/0144487 A1	07/29/2004	Martinez et al.		
	A2	US 2003/0134489 A1	07/17/2003	Schwarzenbach et al.		
	A3	US 2003/0077885 A1	04/24/2003	Aspar et al.		
	A4	US 2002/0025604 A1	02/28/2003	Tiwari		
	A5	US 6,593,212 B1	07/15/2003	Kub et al.		
	A6	US 6,362,077 B1	03/26/2002	Aspar et al.		
	A7	US 6,303,468 B1	10/16/2001	Aspar et al.		
	A8	US 6,225,192	05/01/2001	Aspar et al.		
	A9	US 6,020,252	02/01/2000	Aspar et al.		

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER <small>Number-Kind Code (if known)</small>	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
	A10	FR 2 847 075 A1	05/14/2004	France		Abstract
	A11	FR 2 767 416 A1	02/19/1999	France		Abstract
	A12	WO 2004/044976 A1	05/27/2004	PCT		Abstract
	A13	WO 03/013815 A1	02/20/2003	PCT		Abstract
	A14	WO 02/083387 A1	10/24/2002	PCT		Abstract
	A15	WO 00/63965	10/26/2000	PCT		
	A16	EP 0 994 503 A1	04/19/2000	EPO		Abstract
	A17	EP 02 293 049 A1	05/20/1988	EPO		
	A18	EP 02 293 049 B1	05/20/1988	EPO		

EXAMINER INITIAL	OTHER ART - NON PATENT LITERATURE DOCUMENTS <small>(Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.</small>	
	A19	Argawal et al., "Efficient Production of Silicon-on-Insulator Films by Co-Implantation of He+ with H+," <i>Applied Physics Letters</i> , Volume 72, Number 9, 2 March 1998 ; pp. 1086-1088.
	A20	Cerofolini et al., <i>Materials Science and Engineering</i> , B71 - 2000, pp. 196-202.
	A21	Henttinen et al., <i>Applied Physics Letters</i> , Volume 16, Number 17, 24 April 2000; pp. 2370-2372.

EXAMINER /Daniel Luke/	DATE CONSIDERED 06/15/2009
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /DL/